

<b>Notice of References Cited</b>	Application/Control No. 10/751,629	Applicant(s)/Patent Under Reexamination KWAK ET AL.
	Examiner David Q. Nguyen	Art Unit 2617

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2005/0096063	05-2005	Muniere, Vincent	455/452 2
*	B	US-2002/0191556	12-2002	Krishnarajah et al.	370/221
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
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	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

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